

**Design and test technology for dependable systems-on-chip**

2011 [https://www.ester.ee/record=b4467408\\*est](https://www.ester.ee/record=b4467408*est)

**Fehler in Automaten**

1989 [http://www.ester.ee/record=b2015320\\*est](http://www.ester.ee/record=b2015320*est)

**Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia**

2012 [http://www.ester.ee/record=b2777270\\*est](http://www.ester.ee/record=b2777270*est)